Notice of References Cited Application/Control No. 10/585,660 Applicant(s)/Patent Under Reexamination ATSUMI ET AL. Examiner MARK WOODALL 3742 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,944,922 A	07-1990	Hayashi, Hidechika	422/509
*	В	US-5,017,796 A	05-1991	Makita, Haruomi	250/559.38
*	С	US-5,122,648 A	06-1992	Cohen et al.	250/201.3
*	D	US-5,594,235 A	01-1997	Lee, Ken K.	250/201.3
*	Е	US-6,353,216 B1	03-2002	Oren et al.	250/201.3
*	F	US-6,411,838 B1	06-2002	Nordstrom et al.	600/476
*	G	US-2002/0153500 A1	10-2002	Fordahl et al.	250/559.29
*	Η	US-2004/0206882 A1	10-2004	Banks et al.	250/201.2
*	1	US-2008/0037003 A1	02-2008	Atsumi et al.	356/72
*	J	US-2008/0218735 A1	09-2008	Atsumi et al.	356/72
*	K	US-2009/0166342 A1	07-2009	Kuno et al.	219/121.67
*	L	US-7,595,895 B2	09-2009	Kurita et al.	356/614
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP 06190578 A	07-1994	Japan	KUBOTA, SATORU	B23K 26/04
	0	JP 2000306865 A	11-2000	Japan	FUJITA et al.	H01L 21/301
	Ρ					
	Ø					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.